

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination DAVE ET AL.	
		Examiner John D. Lee	<i>John D. Lee</i> Art Unit 2874	

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	V	Rollins et al, "Optimal Interferometer Designs For Optical Coherence Tomography", OPTICS LETTERS, vol. 24, no. 21, November 1, 1999, pp. 1484-1486.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.